

Preliminary

SIGC156T60SNR2C

IGBT Chip in NPT-technology

FEATURES:

- 600V NPT technology
- 100µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

IGBT-Modules **Applications:** drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC156T60SNR2C	600V	200A	12.5 x 12.5 mm ²	sawn on foil	Q67050-A4154- A003

MECHANICAL PARAMETER:

Raster size	12.5 x 12.5				
Area total / active	156.25 / 138.2				
Emitter pad size	8x(2.58x4.78)				
Gate pad size	0.8 x 1.46				
Thickness	100	μm			
Wafer size	150				
Flat position	90	deg			
Max.possible chips per wafer	84				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	Al, ≤500μm				
Reject Ink Dot Size	Ø 0.65mm; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month				



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MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V _{CE}	600	V
DC collector current, limited by T _{jmax}	I _C	200	Α
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	400	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
. u.u.iiotoi			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	V _{GE} =0V, I _C =5mA	600			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =200A	1.6	2	2.5	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	I _C =4mA, V _{GE} =V _{CE}	3	4	5	
Zero gate voltage collector current	I _{CES}	V _{CE} =600V, V _{GE} =0V			700	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V, V _{GE} =30V			600	nA
Integrated gate resistor	R _{Gint}			5		Ω

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
raiametei			min.	typ.	max.	Onic
Input capacitance	Ciss	V _{CE} =25V	-	tbd	-	nF
Output capacitance	Coss	$V_{GE}=0V$	-	tbd	-	
Reverse transfer capacitance	Crss	<i>f</i> =1MHz	-	tbd	-	

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

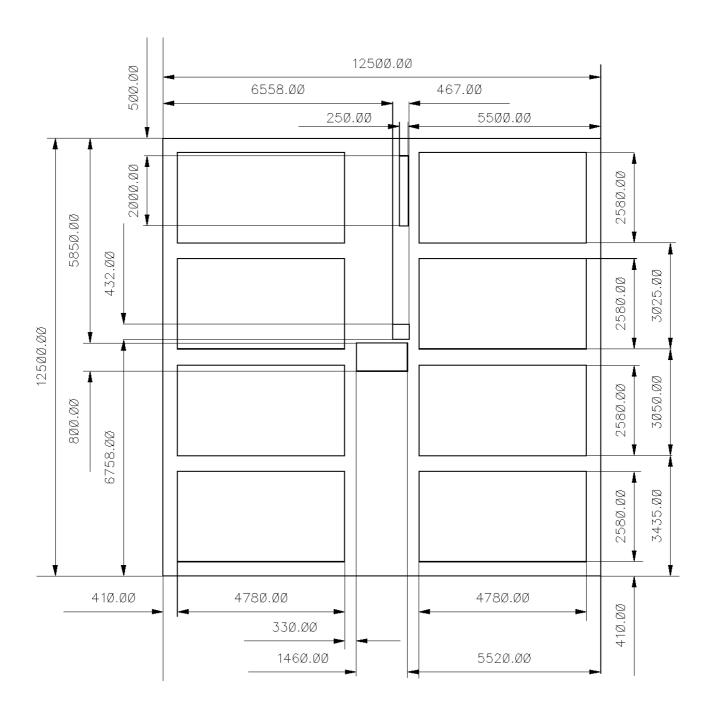
Parameter	Symbol	Conditions*	Value			Unit
raidilletei	Symbol	Conditions	min.	typ.	max.	Onit
Turn-on delay time	$t_{d(on)}$	$T_{\rm j} = 150^{\circ} \text{C}$	-	tbd	-	ns
Rise time	$t_{\rm r}$	$V_{CC}=400V$ $I_{C}=200A$	-	tbd	-	
Turn-off delay time	t _{d(off)}	V_{GE} =+15/0V R_{G} = Ω	-	tbd	-	
Fall time	t_{f}	71G = 32	-	tbd	-	

^{*} switching conditions different to 600V LowLoss, under comparable switching conditions 40% faster turnoff than LowLoss



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CHIP DRAWING:





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FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

BSM 200 GD 60 DLC

Econo Pack 3

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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